Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/662,656	BARCHI ET AL.	
Examiner	Art Unit	_
Flien C. Tran	2134	

SEARCHED			
Class	Subclass	Date	Examiner
726	8	6/8/2006	ECT
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	6/8/2006	ECT